# **Power MOSFET**

# 60 V, 27.4 m $\Omega$ , 17 A, Single N-Channel

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

# MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage		$V_{DSS}$	60	V	
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain Cur-		T <sub>C</sub> = 25°C	I <sub>D</sub>	17	Α
rent R <sub>θJC</sub> (Notes 1 & 3)	Steady	T <sub>C</sub> = 100°C		12	
Power Dissipation R <sub>θJC</sub>	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	18	W
(Note 1)		T <sub>C</sub> = 100°C		9.1	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	7.5	Α
Current $R_{\theta JA}$ (Notes 1, 2 & 3)		T <sub>A</sub> = 100°C		5.3	
Power Dissipation R <sub>θJA</sub>		T <sub>A</sub> = 25°C	P <sub>D</sub>	3.4	W
(Notes 1 & 2)		T <sub>A</sub> = 100°C		1.7	
Pulsed Drain Current	$T_{A} = 25^{\circ}$	$C, t_p = 10  \mu s$	I <sub>DM</sub>	77	Α
Operating Junction and S	Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Source Current (Body Diode)			IS	20	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 1 A)			E <sub>AS</sub>	48	mJ
Lead Temperature for Sol (1/8" from case for 10 s)	dering Pu	rposes	T <sub>L</sub>	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Note 1)	$R_{\theta JC}$	8.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	44	

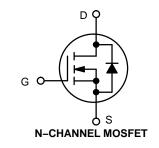
- 1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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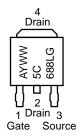
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	
60 V	27.4 mΩ @ 10 V	17 A	
00 V	40 mΩ @ 4.5 V	17.8	





**DPAK CASE 369C** STYLE 2

## **MARKING DIAGRAM & PIN ASSIGNMENT**



= Assembly Location

= Year WW = Work Week 5C688L = Device Code = Pb-Free Package

### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Cond	lition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	· · · · · · · · · · · · · · · · · · ·		•		-	-	•
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	V <sub>GS</sub> = 0 V, I <sub>D</sub> :	= 250 μΑ	60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				27		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			10	μΑ
		$V_{DS} = 60 \text{ V}$	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_{D}$	= 15 μΑ	1.2		2.1	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				4.4		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>I</sub>	<sub>O</sub> = 10 A		22.8	27.4	mΩ
	Ī	$V_{GS} = 4.5 \text{ V}, \text{ I}$	<sub>D</sub> = 10 A		32	40	1
Forward Transconductance	9FS	V <sub>DS</sub> = 55 V, I <sub>E</sub>	<sub>O</sub> = 10 A		20		S
CHARGES, CAPACITANCES AND GATE RE	SISTANCES						
Input Capacitance	C <sub>iss</sub>				400		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V, f} = V_{DS} = 25$			170		1
Reverse Transfer Capacitance	C <sub>rss</sub>	VDS - 20	, v		12		
Total Gate Charge	$Q_{G(TOT)}$	V <sub>DS</sub> = 30 V,	V <sub>GS</sub> = 4.5 V		3.4		nC
		$I_D = 10 \text{ A}$	V <sub>GS</sub> = 10 V		7.0		
Threshold Gate Charge	Q <sub>G(TH)</sub>				0.9		nC
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V},$ $I_{D} = 10 \text{ A}$			1.5		
Gate-to-Drain Charge	$Q_{GD}$				1.1		1
Plateau Voltage	V <sub>GP</sub>				2.9		V
SWITCHING CHARACTERISTICS (Note 5)	•				•		
Turn-On Delay Time	t <sub>d(on)</sub>				8		ns
Rise Time	t <sub>r</sub>	Voc = 45 V Vr	oc = 30 V		42		1
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS} = 4.5 \text{ V}, V_{I}$ $I_{D} = 10 \text{ A}, R_{G}$	$= 2.5 \Omega$		11		1
Fall Time	t <sub>f</sub>				24		1
DRAIN-SOURCE DIODE CHARACTERISTIC	s						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.9	1.2	V
		$I_{S} = 10 \text{ A}$	T <sub>J</sub> = 125°C		0.8		
Reverse Recovery Time	t <sub>RR</sub>		1		17		ns
Charge Time	ta	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 10 \text{ A}$			8		
Discharge Time	tb				9		
Reverse Recovery Charge	Q <sub>RR</sub>				10		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### TYPICAL CHARACTERISTICS

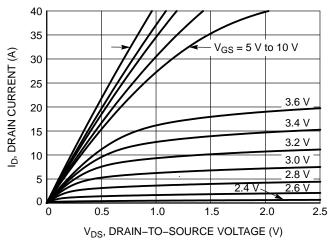


Figure 1. On-Region Characteristics

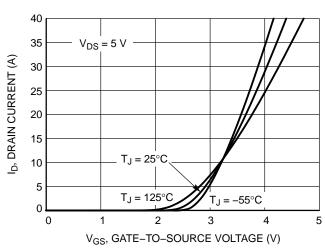


Figure 2. Transfer Characteristics

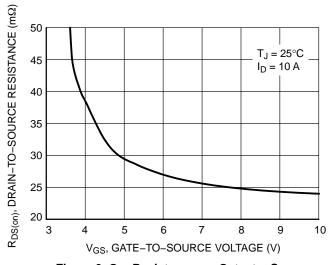


Figure 3. On-Resistance vs. Gate-to-Source Voltage

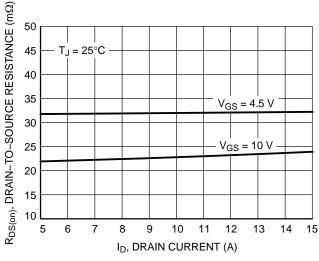


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

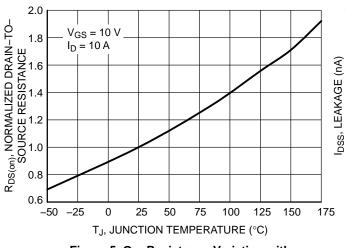


Figure 5. On–Resistance Variation with Temperature

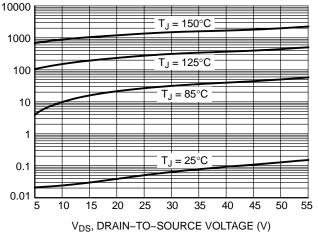


Figure 6. Drain-to-Source Leakage Current vs. Voltage

## **TYPICAL CHARACTERISTICS**

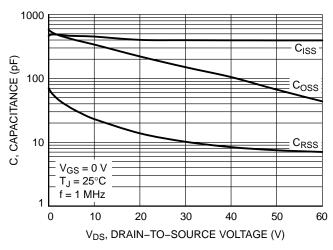


Figure 7. Capacitance Variation

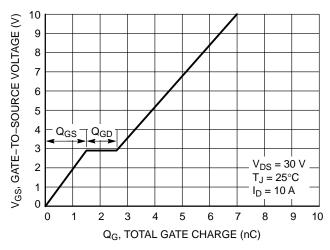


Figure 8. Gate-to-Source vs. Total Charge

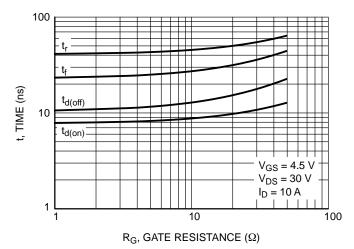


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

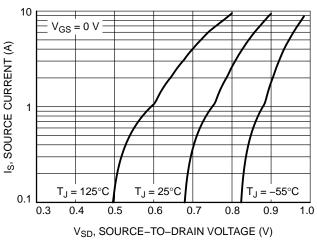


Figure 10. Diode Forward Voltage vs. Current

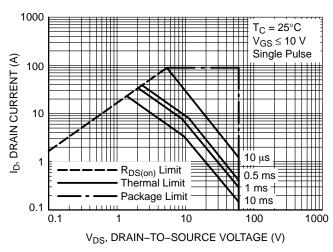


Figure 11. Maximum Rated Forward Biased Safe Operating Area

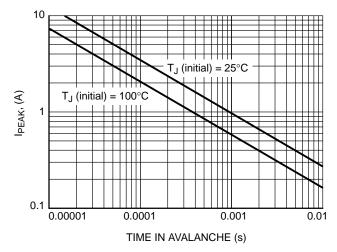


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

# TYPICAL CHARACTERISTICS

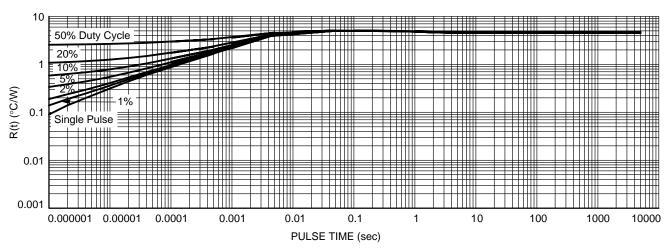


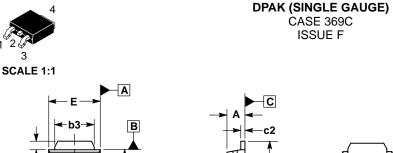
Figure 13. Thermal Response

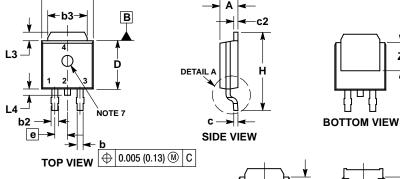
## **ORDERING INFORMATION**

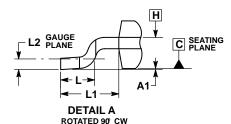
Order Number	Package	Shipping <sup>†</sup>
NTD5C688NLT4G	DPAK (Pb-Free)	2500 / Tape & Reel

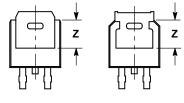
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

**DATE 21 JUL 2015** 





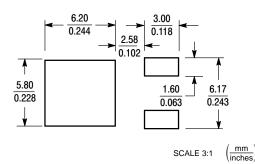




**BOTTOM VIEW** ALTERNATE CONSTRUCTIONS

STYLE 1: PIN 1. BASE 2. COLLE 3. EMITTI 4. COLLE	ER 3. SOL	AIN 2. CATI JRCE 3. ANO	HODE 2. ANODE DE 3. GATE	STYLE 5: PIN 1. GATE 2. ANODE 3. CATHODE 4. ANODE
STYLE 6:	STYLE 7:	3. ANODE	STYLE 9:	STYLE 10:
PIN 1. MT1	PIN 1. GATE		PIN 1. ANODE	PIN 1. CATHODE
2. MT2	2. COLLECTOR		2. CATHODE	2. ANODE
3. GATE	3. EMITTER		3. RESISTOR ADJUST	3. CATHODE
4. MT2	4. COLLECTOR		4. CATHODE	4. ANODE

## **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## NOTES:

z

- IOTES. 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-

- MENSIONS b3, L3 and Z.

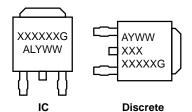
  Jimensions b And E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

  MENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

  6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

		INC	HES	MILLIM	IETERS
	DIM	MIN	MAX	MIN	MAX
	Α	0.086	0.094	2.18	2.38
	A1	0.000	0.005	0.00	0.13
	b	0.025	0.035	0.63	0.89
ĺ	b2	0.028	0.045	0.72	1.14
	b3	0.180	0.215	4.57	5.46
	С	0.018	0.024	0.46	0.61
	c2	0.018	0.024	0.46	0.61
	D	0.235	0.245	5.97	6.22
	Е	0.250	0.265	6.35	6.73
	е	0.090	BSC	2.29	BSC
	Н	0.370	0.410	9.40	10.41
	L	0.055	0.070	1.40	1.78
	L1	0.114	REF	2.90	REF
ĺ	L2	0.020	BSC	0.51	BSC
	L3	0.035	0.050	0.89	1.27
	L4		0.040		1.01
	Z	0.155		3.93	

## **GENERIC MARKING DIAGRAM\***



XXXXXX = Device Code = Assembly Location Α L = Wafer Lot Υ = Year

WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

DOCUMENT NUMBER:	98AON10527D	E
STATUS:	ON SEMICONDUCTOR STANDARD	a ve
NEW STANDARD:	REF TO JEDEC TO-252	"(
DESCRIPTION:	DPAK SINGLE GAUGE SURFACE MOU	NT

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PAGE 1 OF 2



<b>DOCUMENT</b>	NUMBER:
98AON10527	7D

PAGE 2 OF 2

ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION. REQ. BY L. GAN	24 SEP 2001
Α	ADDED STYLE 8. REQ. BY S. ALLEN.	06 AUG 2008
В	ADDED STYLE 9. REQ. BY D. WARNER.	16 JAN 2009
С	ADDED STYLE 10. REQ. BY S. ALLEN.	09 JUN 2009
D	RELABELED DRAWING TO JEDEC STANDARDS. ADDED SIDE VIEW DETAIL A. CORRECTED MARKING INFORMATION. REQ. BY D. TRUHITTE.	29 JUN 2010
E	ADDED ALTERNATE CONSTRUCTION BOTTOM VIEW. MODIFIED DIMENSIONS b2 AND L1. CORRECTED MARKING DIAGRAM FOR DISCRETE. REQ. BY I. CAMBALIZA.	06 FEB 2014
F	ADDED SECOND ALTERNATE CONSTRUCTION BOTTOM VIEW. REQ. BY K. MUSTAFA.	21 JUL 2015

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